

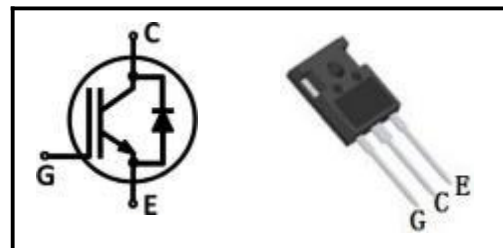
### 特征/Features

- 饱和压降为正温度系数，易于并联使用  
Easy parallel switching capability due to positive temperature coefficient in  $V_{CEsat}$
- 内置快速恢复二极管  
Built-in fast recovery diode
- 高可靠性及热稳定性，良好的参数一致性  
High reliability and thermal stability, good parameter consistency

### 应用领域/Applications

- 太阳能逆变器/Solar Inverter
- 焊接机/Welding Machine
- 不间断电源/UPS
- 功率因数校正/PFC
- PTC加热器/PTC heater
- 气候压缩机Climate compressor

型号/Type	打标/Marking	封装/Package
QMW40N120E	QMW40N120E	TO-247



### 最大额定值/Maximum Rated Values

Item	Symbol	Value	Unit
集电极-发射极电压 Collector-emitter voltage	$V_{CE}$	1200	V
集电极电流 DC collector current, limited by $T_{vjmax}$ $T_C=25^\circ C$ $T_C=130^\circ C$	$I_C$	80 40	A
集电极脉冲电流 Pulsed collector current, $t_p$ limited by $T_{jmax1}$	$I_{Cpuls}$	160	
二极管正向电流 Diode forward current, limited by $T_{jmax}$ $T_C=25^\circ C$ $T_C=100^\circ C$	$I_F$	80 40	
二极管脉冲电流 Diode pulsed current, $t_p$ limited by $T_{jmax1}$	$I_{Fpuls}$	160	V
栅极-发射极电压 Gate-emitter voltage	$V_{GE}$	$\pm 20$	
瞬态栅极-发射极电压 Transient Gate-emitter voltage ( $t_p \leq 10\mu s, D < 0.01$ )		$\pm 30$	
耗散功率 Power dissipation $T_C=25^\circ C$ $T_C=100^\circ C$	$P_{tot}$	428	W
		214	
工作结温 Operating junction temperature	$T_j$	-40~175	°C
储存温度 Storage temperature	$T_{stg}$	-55~150	
焊接温度 Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s		260	
安装扭矩, M3 螺钉最大安装过程: 3 Mounting torque, M3 screw Maximum of mounting processes: 3	$M$	0.6	Nm

1) Defined by design. Not subject to production test.

## 电学特性/Electrical Characteristics

### 静态特性/Static Characteristics (at $T_j=25^\circ\text{C}$ unless otherwise specified)

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
集电极-发射极击穿电压 Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V$ , $I_C=0.25mA$	1200	-	-	V
集电极-发射极饱和电压 Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V$ , $I_C=40A$ $T_j=25^\circ\text{C}$	-	1.7	2.0	
		$T_j=150^\circ\text{C}$	-	2.0	-	
		$T_j=175^\circ\text{C}$	-	2.1	-	
阈值电压 G-E threshold voltage	$V_{GE(th)}$	$I_C=1.5mA$ , $V_{CE}=V_{GE}$	5.0	5.8	6.5	
集电极-发射极漏电流 C-E leakage current	$I_{CES}$	$V_{CE}=1200V$ , $V_{GE}=0V$ $T_j=25^\circ\text{C}$	-	-	0.01	mA
		$T_j=175^\circ\text{C}$	-	-	4.0	
栅极-发射极漏电流 G-E leakage current	$I_{GES}$	$V_{CE}=0V$ , $V_{GE}=20V$	-	-	250	nA

### 动态特性/Dynamic Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
输入电容 Input capacitance	$C_{iss}$	$V_{CE}=25V$ , $V_{GE}=0V$ , $f=1MHz$	-	9900	-	pF
输出电容 Output capacitance	$C_{oss}$		-	102	-	
反馈电容 Reverse transfer capacitance	$C_{rss}$		-	102	-	
栅电荷 Gate charge	$Q_G$	$V_{CC}=400V$ , $I_C=40A$ , $V_{GE}=15V$	-	467	-	nC

### 热学特性/Thermal Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
结-外壳热阻 IGBT thermal resistance, junction-case	$R_{thJC}$	-	-	0.28	0.35	K/W
二极管结-外壳热阻 Diode thermal resistance, junction-case	$R_{thJCD}$	-	-	-	0.80	
结-环境热阻 Thermal Resistance, junction-ambient	$R_{thJA}$	-	-	-	40	

**IGBT开关特性(感性负载) / IGBT Switching Characteristics**

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit	
开通延迟时间 Turn-on delay time	$t_{d(on)}$	$T_J=25^{\circ}C,$ $V_{CC}=600V,$ $I_C=40A,$ $V_{GE}=0/15V,$ $R_G=10\Omega,$ <i>Inductive load</i>	-	113	-	ns	
上升时间 Rise time	$t_r$		-	76	-		
关断延迟时间 Turn-off delay time	$t_{d(off)}$		-	738	-		
下降时间 Fall time	$t_f$			-	80	-	
开通损耗 Turn-on energy	$E_{on}$			-	2.56	-	mJ
关断损耗 Turn-off energy	$E_{off}$			-	2.13	-	
开关损耗 Total switching energy	$E_{ts}$			-	4.69	-	
开通延迟时间 Turn-on delay time	$t_{d(on)}$		$T_J=175^{\circ}C,$ $V_{CC}=600V,$ $I_C=40A,$ $V_{GE}=0/15V,$ $R_G=10\Omega,$ <i>Inductive load</i>	-	118	-	ns
上升时间 Rise time	$t_r$			-	54	-	
关断延迟时间 Turn-off delay time	$t_{d(off)}$	-		738	-		
下降时间 Fall time	$t_f$			-	162	-	
开通损耗 Turn-on energy	$E_{on}$			-	3.62	-	mJ
关断损耗 Turn-off energy	$E_{off}$			-	3.54	-	
开关损耗 Total switching energy	$E_{ts}$			-	7.16	-	

**二极管开关特性/Diode Characteristics**

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
二极管正向压降 Diode forward voltage	$V_F$	$V_{GE}=0V, I_F=40A$ $T_J=25^{\circ}C$	-	2.4	3.0	V
		$T_J=150^{\circ}C$	-	2.1	-	
		$T_J=175^{\circ}C$	-	2.0	-	
反向恢复时间 Diode reverse recovery time	$t_{rr}$	$T_J=25^{\circ}C,$ $V_R=400V,$ $I_F=40A,$ $di_F/dt=600A/\mu s$	-	165	-	ns
反向恢复电荷 Diode reverse recovery charge	$Q_{rr}$		-	1.49	-	$\mu C$
反向恢复峰值电流 Diode peak reverse recovery current	$I_{rrm}$		-	20.0	-	A

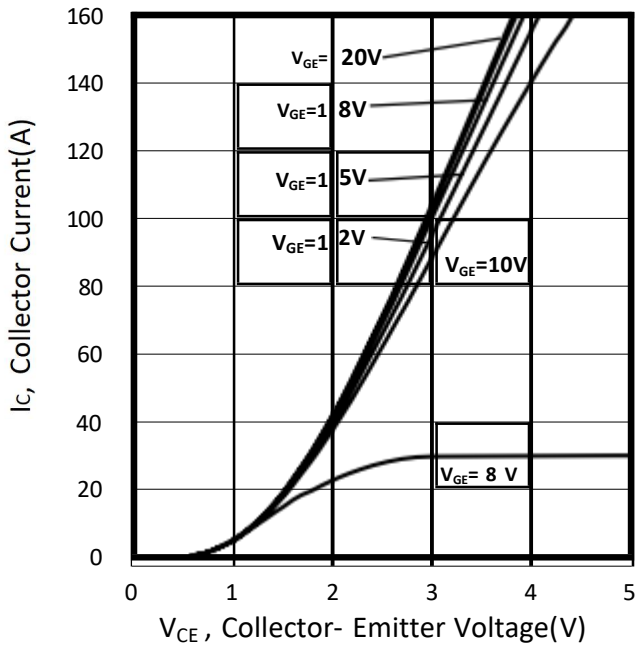


Figure 1. 典型输出特性/Typical output characteristic ( $T_{vj}=25^{\circ}\text{C}$ )

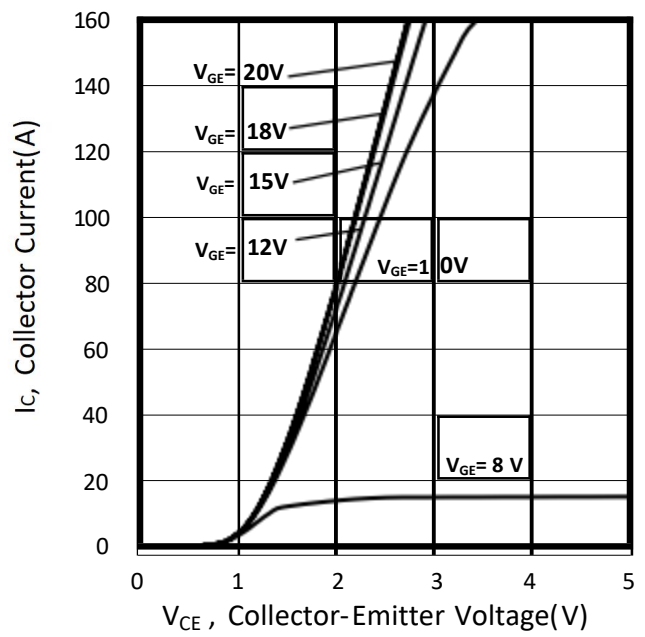


Figure 2. 典型输出特性/Typical output characteristic ( $T_{vj}=175^{\circ}\text{C}$ )

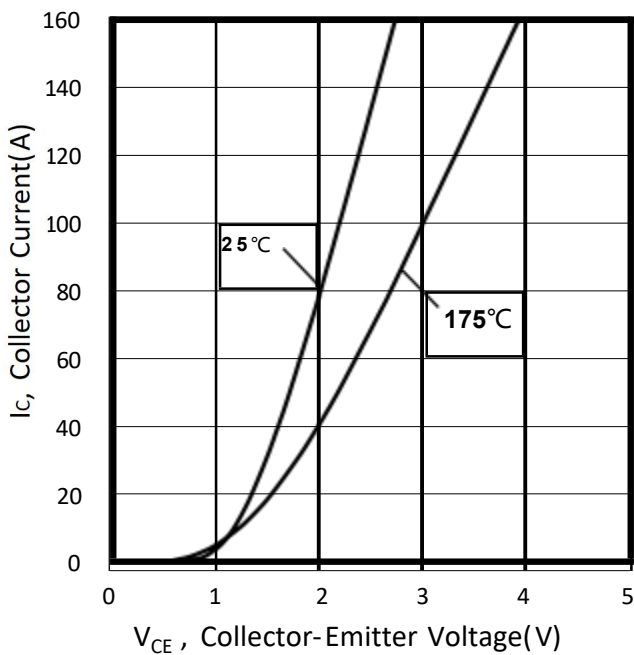


Figure 3. 典型  $V_{CE(sat)}-T_j$  特性曲线/  
Typical  $V_{CE(sat)}-T_j$  characteristic  
( $V_{GE}=15\text{V}$ )

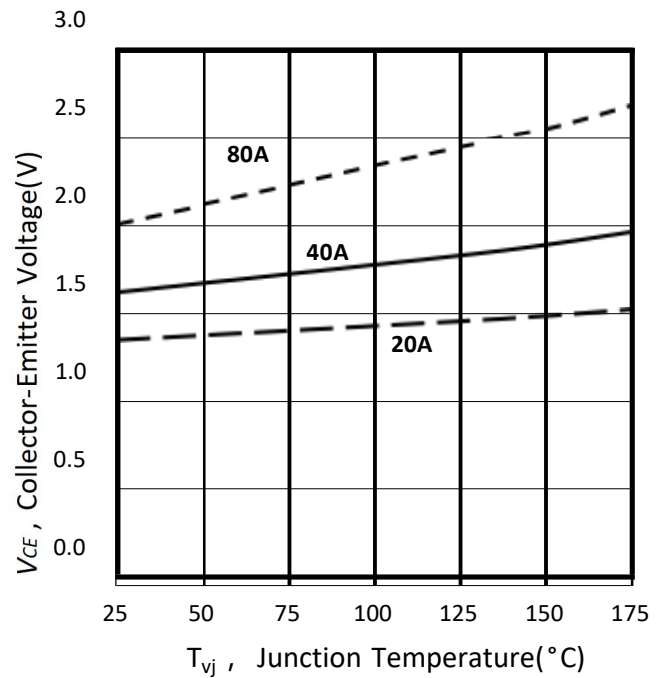
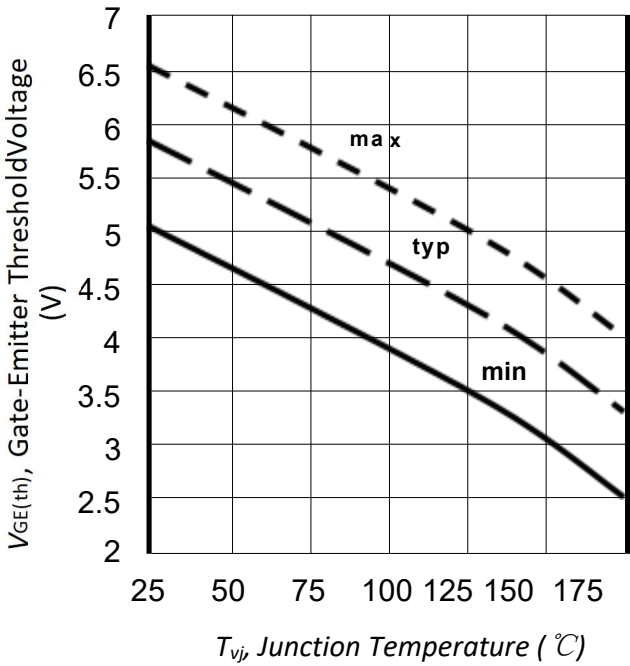
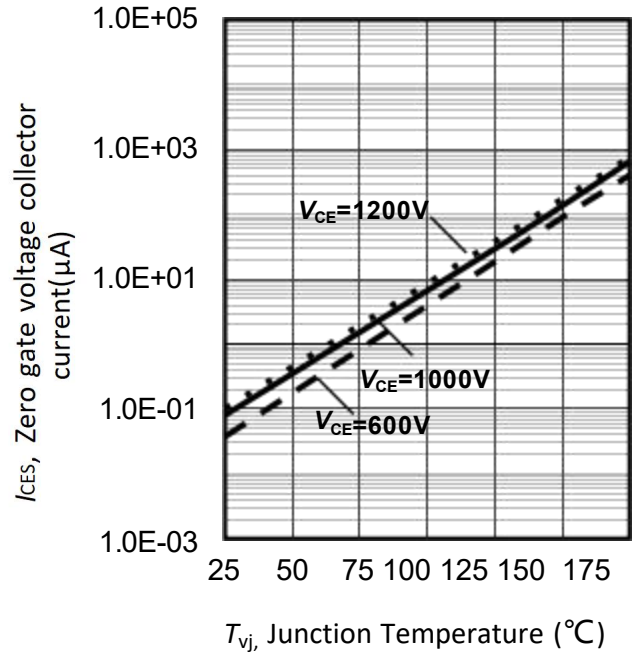


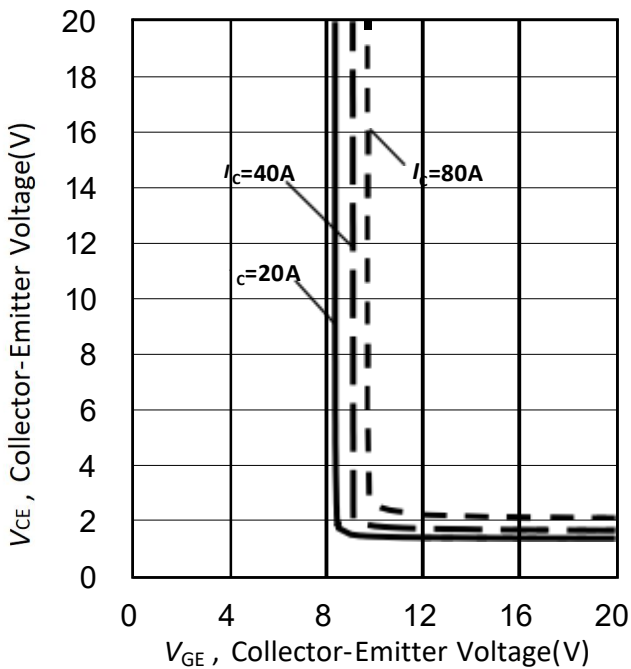
Figure 4. 典型  $V_{CE(sat)}-T_j$  特性曲线/Typical  
 $V_{CE(sat)}-T_j$  characteristic  
( $V_{GE}=15\text{V}$ )



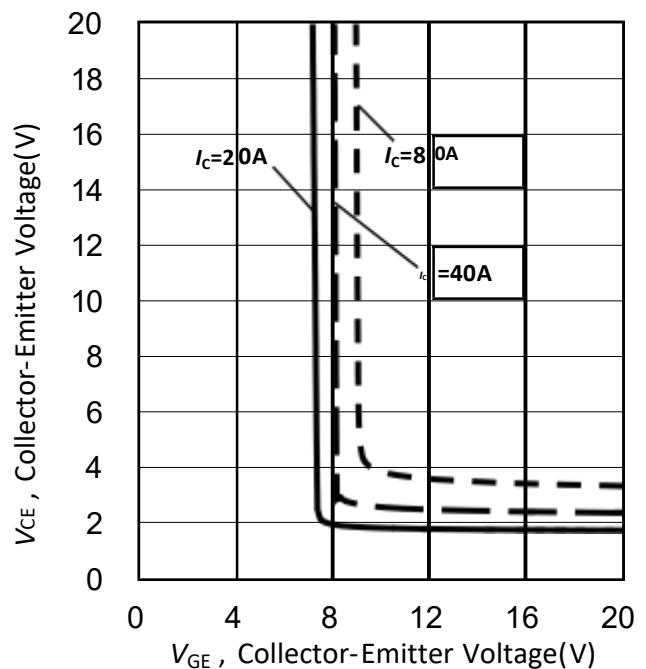
**Figure 5.** 典型  $V_{GE(th)}$ - $T_j$  特性曲线/Typical  $V_{GE(th)}$ - $T_j$  characteristic ( $I_c=1.5mA$ )



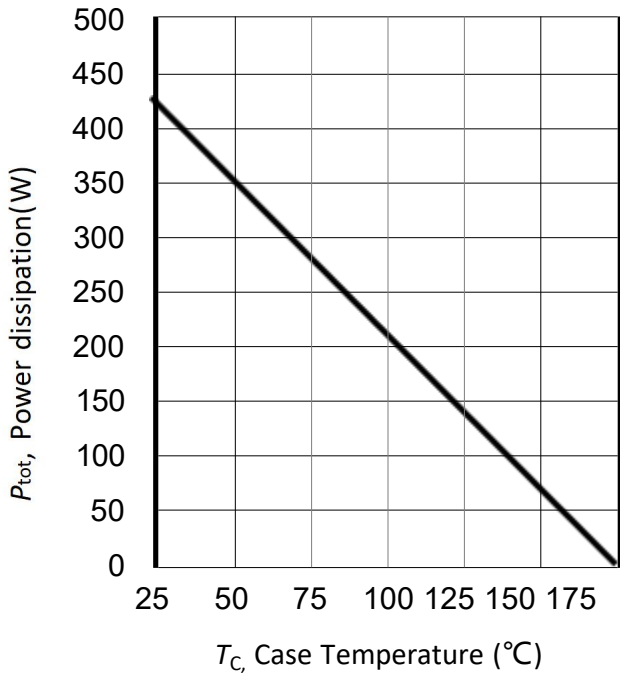
**Figure 6.** 典型  $I_{CES}$ - $T_j$  特性曲线/Typical  $I_{CES}$ - $T_j$  characteristic ( $V_{GE}=0V$ )



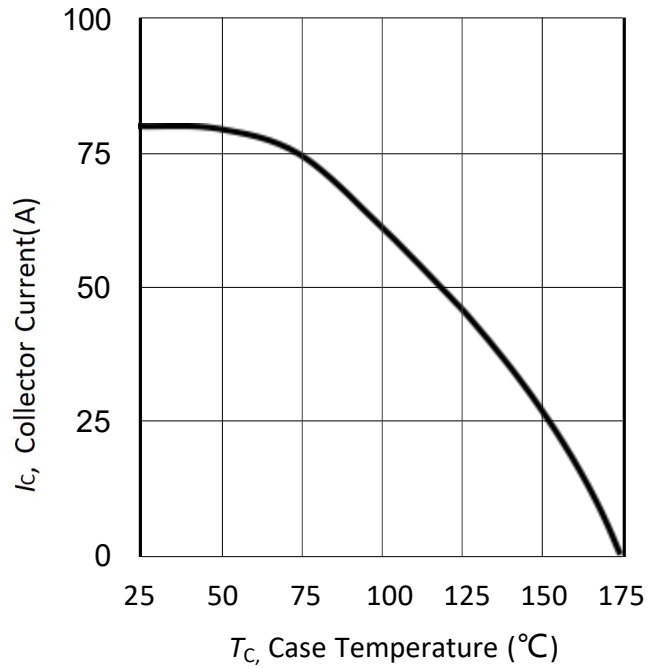
**Figure 7.** 典型  $V_{CE(sat)}$ - $V_{GE(th)}$  特性曲线/Typical  $V_{CE(sat)}$ - $V_{GE(th)}$  characteristic ( $T_{vj}=25^{\circ}C$ )



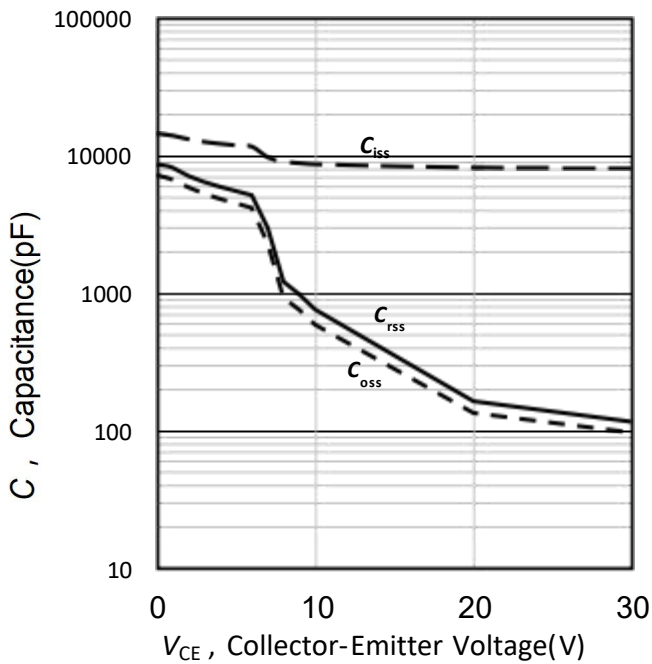
**Figure 8.** 典型  $V_{CE(sat)}$ - $V_{GE(th)}$  特性曲线/Typical  $V_{CE(sat)}$ - $V_{GE(th)}$  characteristic ( $T_{vj}=175^{\circ}C$ )



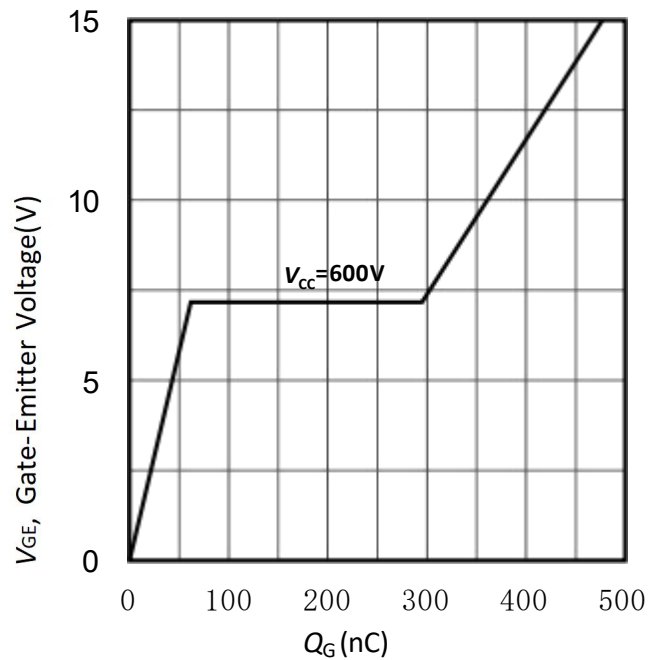
**Figure 9.** 功耗与外壳温度的关系/Power dissipation as a function of case temperature ( $T_{vj} \leq 175^\circ\text{C}$ )



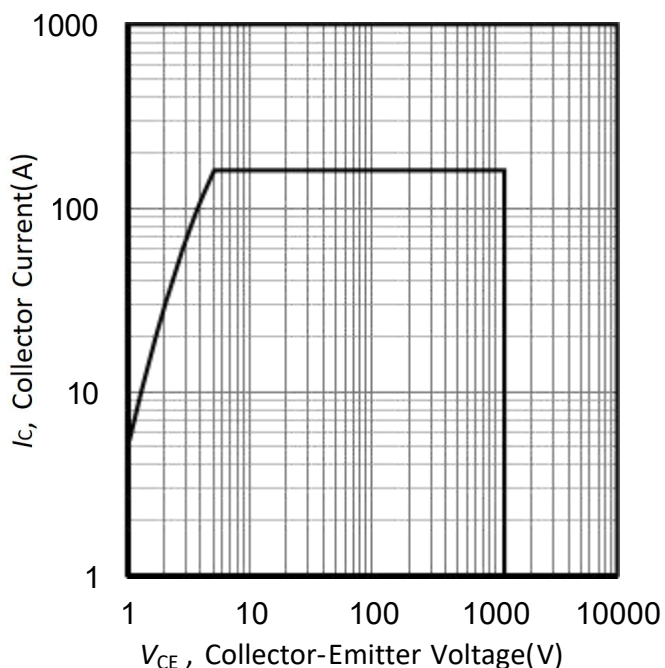
**Figure 10.** 集电极电流与外壳温度的关系/Collector current as a function of case temperature ( $T_{vj} \leq 175^\circ\text{C}, V_{GE} \geq 15\text{V}$ )



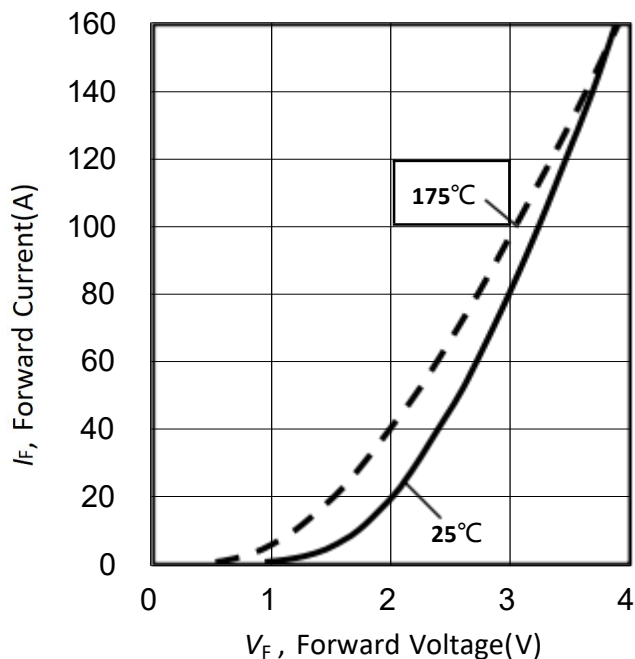
**Figure 11.** 典型电容与集电极-发射极电压的关系 /Typical capacitance as a function of collector-emitter voltage ( $V_{GE}=0\text{V}, f=1\text{MHz}$ )



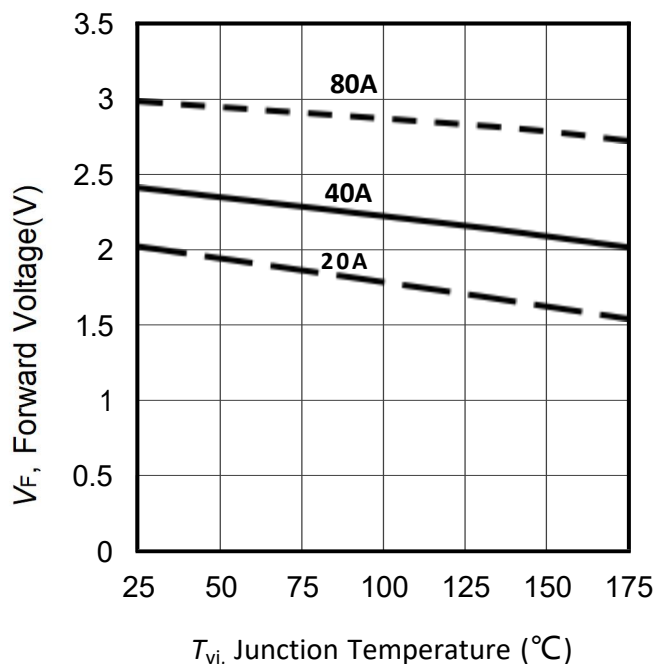
**Figure 12.** 典型栅极电荷/Typical gate charge



**Figure 13. IGBT反向偏置安全工作区/IGBT reverse bias safe operating area**  
( $T_{vj} \leq 175^{\circ}\text{C}$ ,  $V_{GE}=15\text{V}$ )



**Figure 14. 典型二极管正向电流与正向电压的函数关系/Typical diode forward current as a function of forward voltage**



**Figure 15. 典型二极管正向电压为结温函数/Typical diode forward voltage as a function of junction temperature**

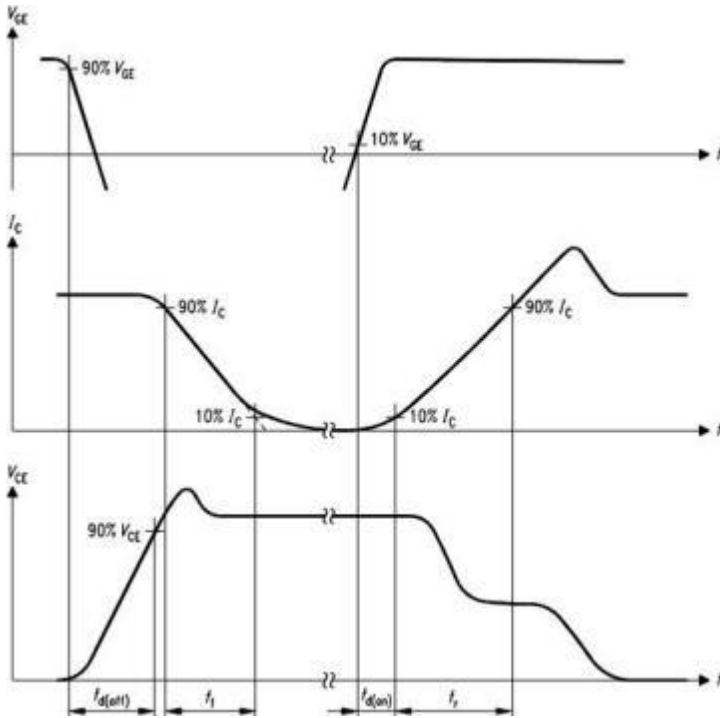


Figure A. 开关时间的定义/Definition of switching times

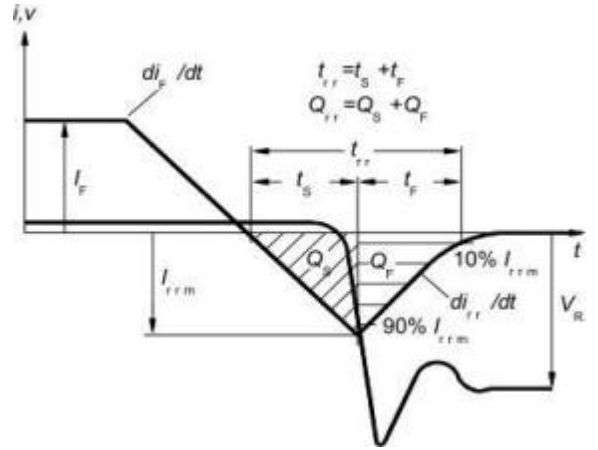


Figure C. 二极管开关特性的定义/Definition of diodes switching characteristics

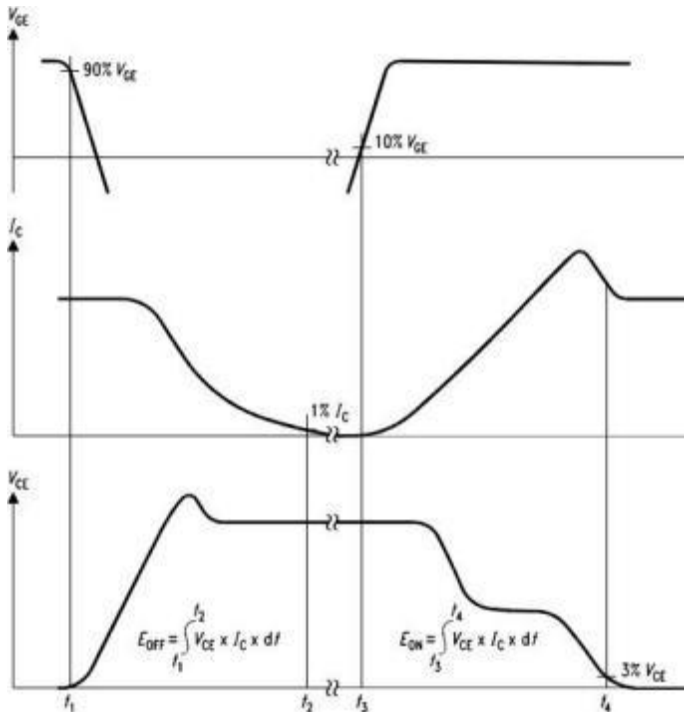


Figure B. 开关损耗的定义/Definition of switching losses

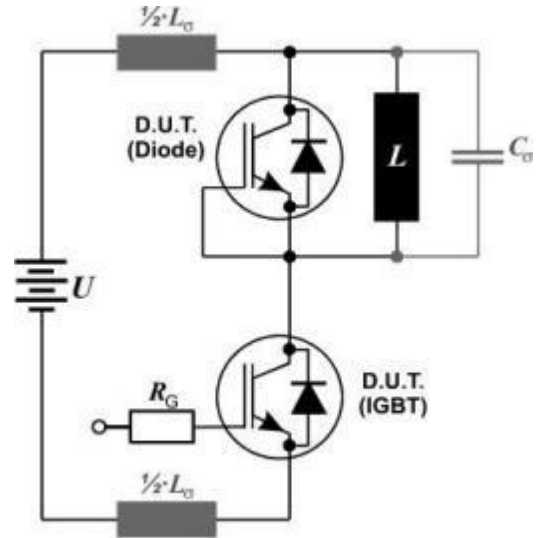
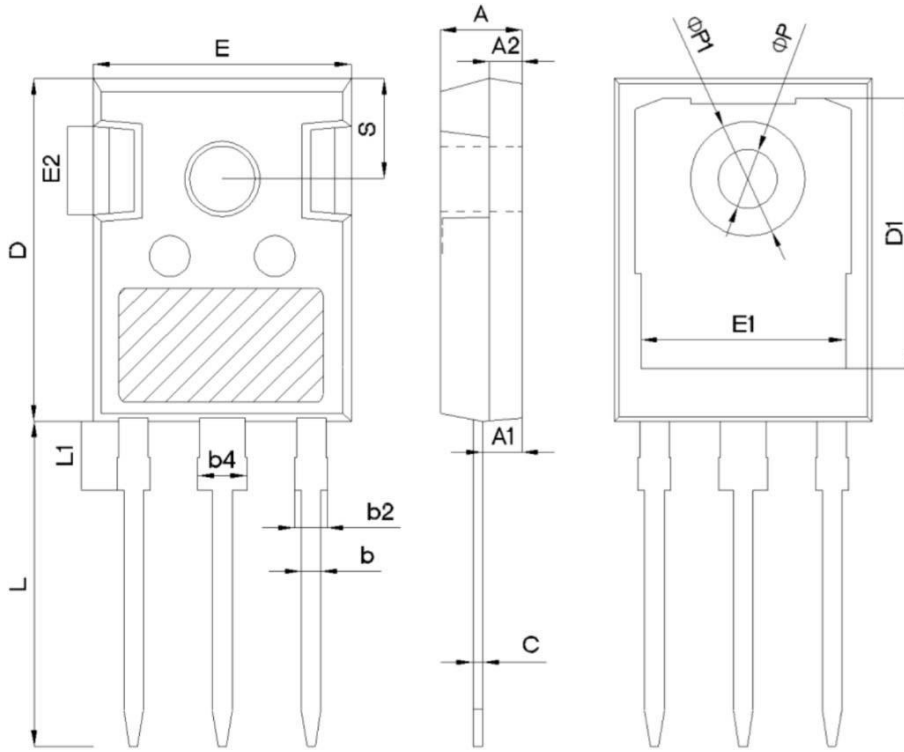


Figure D. 开关测试电路/Switching test circuit



**TO-247**


SYMBOL	mm		
	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.21	2.41	2.61
A2	1.85	2.00	2.15
b	1.11	1.21	1.36
b2	1.91	2.01	2.21
b4	2.91	3.01	3.21
c	0.51	0.61	0.75
D	20.70	21.00	21.30
D1	16.25	16.55	16.85
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.80	5.00	5.20
E3	2.30	2.50	2.70
e	5.44BSC		
L	19.62	19.92	20.22
L1	-	-	4.30
ΦP	3.40	3.60	3.80
ΦP1	-	-	7.30
S	6.15BSC		

**修订历史/Revision History:**

修订 /Revision	主题（自上次修订以来的主要变化） /Subjects (major changes since last revision)	日期 /Date
1.0	Initial Version	2022-06
2.0	Update the English and Chinese versions	2023-04

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